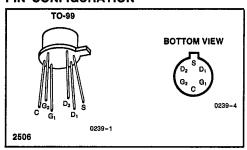
3N165, 3N16

3N165, 3N166Monolithic Dual P-Channel Enhancement Mode MOSFET General Purpose Amplifier

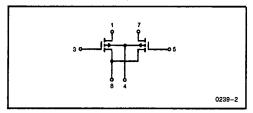
FEATURES

- Very High Impedance
- High Gate Breakdown
- Low Capacitance

PIN CONFIGURATION



DEVICE SCHEMATIC



ABSOLUTE MAXIMUM RATINGS (Note 1)

 (TA = 25°C unless otherwise specified)

 Drain-Source or Drain-Gate Voltage (Note 2)

 3N165
 40V

 3N166
 30V

 Transient Gate-Source Voltage (Note 3)
 ±125

 Gate-Gate Voltage
 ±80V

 Drain Current (Note 2)
 50mA

 Storage Temperature
 -65°C to +200°C

 Operating Temperature
 -55°C to +155°C

 Lead Temperature (Soldering, 10sec)
 +300°C

 Power Dissipation
 300mW

 Both Sides
 525mW

 Total Derating above 25°C
 4.2mW/°C

NOTE: Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions above those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

ORDERING INFORMATION

TO-99
3N165
3N166

ELECTRICAL CHARACTERISTICS (T_A = 25°C and V_{BS} = 0 unless otherwise specified)

Symbol	Parameter Gate Reverse Leakage Current	Test Conditions V _{GS} =40V		Limits		Units
				Min	Max	
IGSSR					10	
lgssf	Gate Forward Leakage Current	V _{GS} = -40V			-10	
			T _A = + 125°C		-25	pΑ
loss	Drain to Source Leakage Current	V _{DS} = -20V	V _{DS} = -20V		-200	
I _{SDS}	Source to Drain Leakage Current	$V_{SD} = -20, V_{DB} = 0$			-400	
[†] D(on)	On Drain Current	V _{DS} =-15V, V _{GS} =-10V		-5	-30	mA
V _{GS(th)}	Gate Source Threshold Voltage	$V_{DS} = -15V$, $I_D = -10\mu A$		-2	-5	v
V _{GS(th)}	Gate Source Threshold Voltage	$V_{DS} = V_{GS}, I_D = -10 \mu A$		-2	-5	L. "
r _{DS(on)}	Drain Source ON Resistance	$V_{GS} = -20V, I_{D} = -100 \mu A$			300	ohms

INTERSIUS SOLE AND EXCLUSIVE WARRANTY OBLIGATION WITH RESPECT TO THIS PRODUCT SHALL BE THAT STATED IN THE WARRANTY ARTICLE OF THE CONDITION OF SALE.
THE WARRANTY SHALL BE EXCLUSIVE AND SHALL BE IN LIEU OF ALL OTHER WARRANTIES, EXPRESS, IMPLIED OR STATUTORY, INCLUDING THE IMPLIED WARRANTIES OF
MERCHANTABILITY AND FITNESS FOR A PARTICULAR USE.

NOTE: All typical values have been characterized but are not tested.

3N165, 3N166

GINTERSIL

T-29-27

ELECTRICAL CHARACTERISTICS (Continued) (T_A = 25°C and V_{BS} = 0 unless otherwise specified)

Symbol	Parameter	Test Conditions		Limits	
				Max	Units
9fs	Forward Transconductance	$V_{DS} = -15V$, $I_D = -10mA$, $f = 1kHz$	1500	3000	μs
gos	Output Admittance			300	
Ciss	Input Capacitance			3.0	
Crss	Reverse Transfer Capacitance	V _{DS} = -15V, I _D = -10mA, f=1MHz (Note 4)		0.7	pF
Coss	Output Capacitance		<u></u> .	3.0	<u> </u>
R _E (Y _{fs})	Common Source Forward Transconductance	$V_{DS} = -15V$, $I_D = -10mA$, $f = 100MHz$ (Note 4)	1200		μs

MATCHING CHARACTERISTICS 3N165

Symbol	Parameter	Test Conditions	Limits		Units
		Test Conditions	Min	Max	U 11110
Y _{fs1} /Y _{fs2}	Forward Transconductance Ratio	$V_{DS} = -15V$, $I_D = -500\mu A$, $f = 1kHz$	0.90	1.0	
V _{GS1-2}	Gate Source Threshold Voltage Differential	$V_{DS} = -15V, I_D = -500\mu A$		100	m∨
ΔV _{GS1-2}	Gate Source Threshold Voltage Differential Change with Temperature	$V_{DS} = -15V$, $I_A = -500\mu A$ $T_A = -55^{\circ}C$ to = +25°C		100	μV/°C

NOTES 1. See handling precautions on 3N170 data sheet.

Per transitor.
 Devices must not be tested at ±125V more than once, nor for longer than 300ms.
 For design reference only, not 100% tested.